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Attorney's Docket No.: 04873-074002

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Dvorkis et al.

Art Unit: 2876

Serial No.: 10/050,625

Examiner: Frech, Karl D.

Filed

: January 16, 2002

Title

: OPTICAL SCANNER WITH SEGMENTED COLLECTION MIRROR

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

## **INFORMATION DISCLOSURE STATEMENT**

Applicants submit the references listed on the attached form PTO-1449. Applicants do not concede that the listed references are prior art.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12 2 07

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U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 04873-074002

Application No. 10/050,625

Informati n Disclosure Statement by Applicant (Use several sheets if necessary) Applicant
Dvorkis et al.

Filing Date

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**U.S. Patent Documents** Publication Examiner Desig. Document Filing Date Initial ID Number Date Patentee Class Subclass If Appropriate AA6575368 06/10/03 Tamburrini et al. 5149949 09/22/92 AΒ Wike, Jr. ACAD ΑE AF AG AH ΑI AJ AK

Foreign Patent Documents or Published Foreign Patent Applications									
Examiner	Desig.	Document	Publication	Country or			Translation		
Initial	1D	Number	Date	Patent Office	Class	Subclass	Yes	No	
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					